# SPECIFICATIONS

Customer	利思泰
Product Name	Multi-layer Chip Ferrite Bead
Sunlord Part Number	GZ0603D221TF
Customer Part Number	

[⊠New Released, □Revised]

SPEC No.: GZ10180035

[This SPEC is total 9 pages including specifications and appendix.] [ROHS Compliant Parts]



# Shenzhen Sunlord Electronics Co., Ltd.

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<b>For Customer approv</b> Qualification Status:		Date:	ed
Approved By	Verified By	Re-checked By	Checked By
omments:			

# [Version change history]

Rev.	Effective Date	Changed Contents	Change Reasons	Approved By
01	Mar.07,2018	New release	1	Hai Guo

# 1. Scope

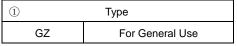
2)

This specification applies to GZ0603D221TF of multi-layer ferrite chip bead.

# 2. Product Description and Identification (Part Number)

- 1) Description:
  - GZ0603D221TF of multi-layer ferrite chip bead. Product Identification (Part Number)

FIUUUC		лі (ган	Number	)	
<u>GZ</u>	<u>0603</u>	<u>D</u>	<u>221</u>	<u>T</u>	<u>F</u>
1	2	3	4	5	6



② External D	Dimensions (L X W)[mm]
0603 [0201]	0.6 X 0.3

Impedance

Nominal Value 220Ω

Nominal

3	Material Code	
	D	

5	Packing		
Т	Tape Carrier Package		

6	HSF Products	
Haz	ardous Substance Free Products	

#### 3. Electrical Characteristics

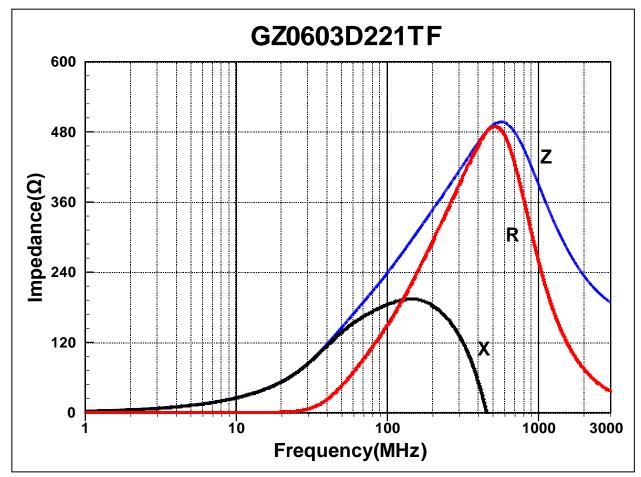
Part Number	Impedance (Ω)	Z Test Freq. (MHz)	DCR (Ω) Max.	Ir (mA) Max.
GZ0603D221TF	220±25%	100	0.90	200

4

Example

221

#### Impedance Frequency Characteristics

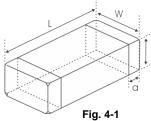


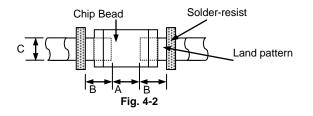
1) Operating and storage temperature range (individual chip without packing):  $-55^{\circ}$ C ~  $+125^{\circ}$ C.

2) Storage temperature range (packaging conditions):-10°C~+40°C and RH 70% (Max.)

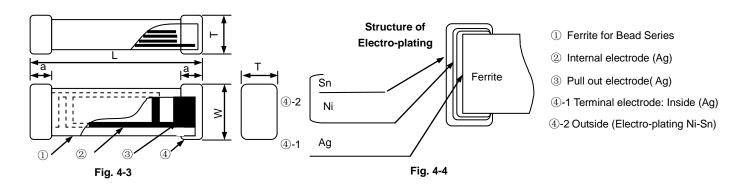
# 4. Shape and Dimensions

- 1) Dimensions and recommended PCB pattern for reflow soldering: See Fig.4-1, Fig.4-2 and Table 4-1.
- 2) Structure: See Fig. 4-3 and Fig. 4-4.





	[ <b>Table 4-1]</b> Unit: mm [inch]		[Table 4-1]				
Туре	L	W	Т	а	А	В	С
0603 [0201]	0.6±0.05 [.024±0.002]	0.3±0.05 [.012±.002]	0.3±0.05 [.012±.002]	0.15±0.05 [.006±.002]	0.2~0.3	0.2~0.3	0.3~0.35



3) Material Information: See Table 4-2.

[Table 4-2]					
Code	Part Name	Material Name			
1)	Ferrite Body	Ferrite Powder			
2	Inner Coils	Silver Paste			
3	Pull-out Electrode (Ag)	Silver Paste			
<b>④-1</b>	Terminal Electrode: Inside Ag Composition				
<b>④-2</b>	Electro-Plating: Ni/Sn plating	Plating Chemicals			

#### 5. Test and Measurement Procedures

## 5.1 Test Conditions

- 5.1.1 Unless otherwise specified, the standard atmospheric conditions for measurement/test as:
  - a. Ambient Temperature: 20±15℃
  - b. Relative Humidity: 65±20%
  - c. Air Pressure: 86kPa to 106kPa
- 5.1.2 If any doubt on the results, measurements/tests should be made within the following limits:
  - a. Ambient Temperature: 20±2°C
  - b. Relative Humidity: 65±5%
  - c. Air Pressure: 86kPa to 106kPa

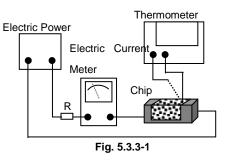
#### 5.2 Visual Examination

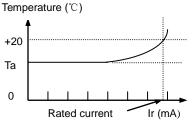
a. Inspection Equipment: 20× magnifier

# 5.3 Electrical Test

- 5.3.1 DC Resistance (DCR)
  - a. Refer to Item 3.
  - b. Test equipment (Analyzer): High Accuracy Milliohmmeter-HP4338B or equivalent.
- 5.3.2 Impedance (Z)
  - a. Refer to Item 3.
  - Test equipment: High Accuracy RF Impedance /Material Analyzer-E4991A or equivalent. Test fixture: HP16197A for 0603, HP16192A for 1005/1608/2012/3216. Test signal: -20dBm or 50mV
  - c. Test frequency refers to Item 3.

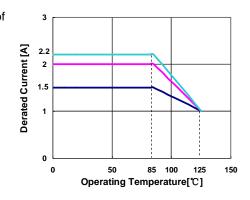
- 5.3.3 Rated Current
  - a. Refer to Item 3.
  - b. Test equipment (see Fig.5.3.3-1): Electric Power, Electric current meter, Thermometer.
  - c. Measurement method (see Fig. 5.3.3-1):
    - 1. Set test current to be 0 mA.
    - 2. Measure initial temperature of chip surface.
    - 3. Gradually increase voltage and measure chip temperature for corresponding current.
  - d. Definition of Rated Current (Ir): Ir is direct electric current as chip surface temperature rose just 20°C against chip initial surface temperature (Ta) (see Fig. 5.3.3-2)







e. When operating temperatures exceeding +85°C, derating of current is necessary for chip ferrite beads for which rated current is 1000mA over. Please apply the derating curve shown in chart according to the operating temperature.



# 5.4 Reliability Test

Items	Requirements	Test Methods and Remarks
5.4.1 Terminal Strength	No removal or split of the termination or other defects shall occur. Chip Chip Glass Epoxy Board	<ol> <li>Solder the bead to the testing jig (glass epoxy board shown in Fig. 5.4.1-1) using leadfree solder. Then apply a force in the direction of the arrow.</li> <li>2N force for 0603 series.</li> <li>Keep time: 10±1s.</li> <li>Speed: 1.0mm/s.</li> </ol>
5.4.2	Fig.5.4.1-1 No visible mechanical damage.	<ol> <li>Solder the bead to the test jig (glass epoxy board shown in Fig.</li> </ol>
Resistance to Flexure	Type         a         b         c           0603[0201]         0.25         0.8         0.3	<ul> <li>Solution the bodd to the test jig (glass opex) bodd shown in Fig. 5.4.2-1) Using a leadfree solder. Then apply a force in the direction shown Fig. 5.4.2-2.</li> <li>Plexure: 2mm.</li> <li>Pressurizing Speed: 0.5mm/sec.</li> <li>Keep time: 30 sec.</li> </ul>
	Unit: mm [inch]	
	b 00 Fig. 5.4.2-1 04.5 04.5 0 0 0 0 0 0 0 0 0 0 0 0 0	45[1.772] Fig. 5.4.2-2
5.4.3 Vibration	<ol> <li>No visible mechanical damage.</li> <li>Impedance change: within ±20%</li> <li>Cu pad Solder mask</li> <li>Glass Epoxy Board</li> <li>Fig. 5.4.3-1</li> </ol>	<ol> <li>Solder the bead to the testing jig (glass epoxy board shown in Fig. 5.4.3-1) using leadfree solder.</li> <li>The bead shall be subjected to a simple harmonic motion having total amplitude of 1.5 mm, the frequency being varied uniformly between the approximate limits of 10 and 55 Hz.</li> <li>The frequency range from 10 to 55 Hz and return to 10 Hz shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3mutually perpendicular directions (total of 6 hours).</li> </ol>
5.4.4 Dropping	<ol> <li>No visible mechanical damage.</li> <li>Impedance change: within ±20%.</li> </ol>	Drop chip bead 10 times on a concrete floor from a height of 100 cm.
5.4.5 Temperature	Impedance change should be within $\pm 20\%$ of initial value measuring at $20^{\circ}$ C.	Temperature range: -55℃ ~ 125℃. Reference temperature: +20℃.
5.4.6 Solderability	<ol> <li>No visible mechanical damage.</li> <li>Wetting shall exceed 75% coverage for 0603 series; exceed 95% for others</li> </ol>	<ol> <li>Solder temperture:240±2°C</li> <li>Duration: 3 sec.</li> <li>Solder: Sn/3.0Ag/0.5Cu.</li> <li>Flux: 25% Resin and 75% ethanol in weight.</li> </ol>
5.4.7 Resistance to Soldering Heat	<ol> <li>No visible mechanical damage.</li> <li>Wetting shall exceed 75% coverage for 0603 series; exceed 95% for others</li> <li>Impedance change: within ±20%.</li> </ol>	<ol> <li>Solder temperature :260±3°C</li> <li>Duration: 5 sec.</li> <li>Solder: Sn/3.0Ag/0.5Cu.</li> <li>Flux: 25% Resin and 75% ethanol in weight.</li> <li>The chip shall be stabilized at normal condition for 1~2 hours before measuring.</li> </ol>

# Specifications for Multi-layer Chip Ferrite Bead

5.4.8	① No mechanical damage.	① Temperature, Time: (See Fig.5.4.8-1)	
Thermal Shock	<ol> <li>Impedance change: Within ±20%.</li> </ol>	-55°C for 30±3 min→125°C for 30±3min.	
		2 Transforming interval: Max. 20 sec.	
	30 min. 30 min.	③ Tested cycle: 100 cycles.	
	125°C	<ul> <li>The chip shall be stabilized at normal condition for 1~2 hours</li> </ul>	
	Ambient /	before measuring.	
	Temperature 30 min.	5	
	-55°C		
	Fig. 5.4.8-1 <sup>20sec.</sup> (max.)		
5.4.9	① No mechanical damage.	① Temperature: -55±2℃	
Resistance to	② Impedance change: within ±20%.	2) Duration: 1000 <sup>+24</sup> hours.	
Low		The chip shall be stabilized at normal condition for 1~2 hours	
Temperature		before measuring.	
5.4.10	① No mechanical damage.	① Temperature: 125±2°C	
Resistance to	② Impedance change: within ±20%.	② Duration: 1000 <sup>+24</sup> hours.	
High		③ The chip shall be stabilized at normal condition for 1~2 hours	
Temperature		before measuring.	
5.4.11	① No mechanical damage.	① Temperature: 60±2°C	
Damp Heat	② Impedance change: Within ±20%.	② Humidity: 90% to 95% RH.	
(Steady States)		③ Duration: 1000 <sup>+24</sup> hours.	
		④ The chip shall be stabilized at normal condition for 1~2 hours	
		before measuring.	
5.4.12	① No visible mechanical damage.	① Temperature: 60±2℃	
Loading Under	② Impedance change: within ±20%.	Humidity: 90% to 95% RH.	
Damp Heat		3 Duration: 1000 <sup>+24</sup> hours.	
		Applied current: Rated current.	
		5 The chip shall be stabilized at normal condition for 1~2 hours	
		before measuring.	
5.4.13	1 No visible mechanical damage.	① Temperature: 125±2℃	
Loading at High	<ol> <li>Impedance change: within ±20%.</li> </ol>	2 Duration: 1000 <sup>+24</sup> hours.	
Temperature		③ Applied current: Rated current.	
(Life Test)		④ The chip shall be stabilized at normal condition for 1~2 hours	
		before measuring.	

# 6. Packaging, Storage

# 6.1 Packaging

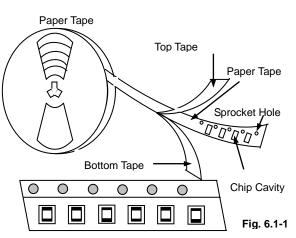
Tape Carrier Packaging:

Packaging code: T

- a. Tape carrier packaging are specified in attached figure Fig.6.1-1~3
- b. Tape carrier packaging quantity please see the following table:

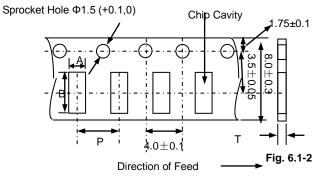
Туре	0603[0201]	
T(mm)	0.3±0.15	
Таре	Paper Tape	
Quantity	15K	

# (1) Taping Drawings (Unit: mm)



Remark: The sprocket holes are to the right as the tape is pulled toward the user.

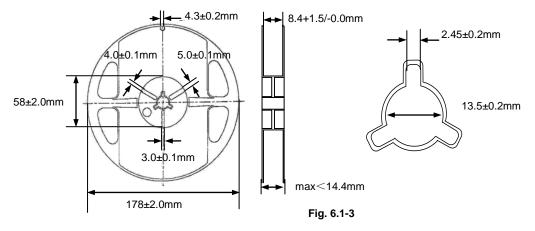
(2) Taping Dimensions (Unit: mm)



Paper Tape

Туре	А	В	Р	T max
0603[0201]	0.40±0.1	0.70±0.1	2.0±0.1	0.55

(3) Reel Dimensions (Unit: mm)



#### 6.2 Storage

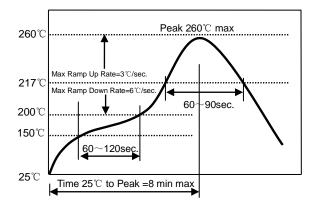
- a. The solderability of the external electrode may be deteriorated if packages are stored where they are exposed to high humidity. Package must be stored at 40°C or less and 70% RH or less.
- b. The solderability of the external electrode may be deteriorated if packages are stored where they are exposed to dust of harmful gas (e.g. HCl, sulfurous gas of H<sub>2</sub>S).
- c. Packaging material may be deformed if package are stored where they are exposed to heat of direct sunlight.
- d. Solderability of the product s with external dimensions as 0603[0201] specified in Clause 5.4.6 shall be guaranteed for 6months from the date of delivery on condition that they are stored at the environment specified in Clause 3. For those parts, which passed more than 6 months shall be checked solder-ability before use.
- e. Solderability of the products, except ones with external dimensions as 0603[0201], specified in Clause 5.4.6 shall be guaranteed for 12 months from the date of delivery on condition that they are stored at the environment specified in Clause 3. For those parts, which passed more than 12 months shall be checked solder-ability before use.

#### 7. Recommended Soldering Technologies

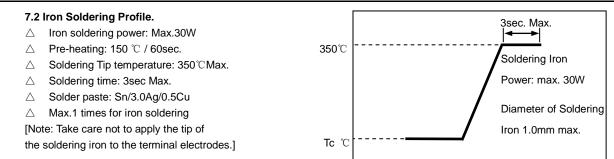
#### 7.1 Re-flowing Profile:

- $\triangle$  Preheat condition: 150 ~200°C/60~120sec.
- $\triangle$  Allowed time above 217°C: 60~90sec.
- △ Max temp: 260°C
- $\triangle$  Max time at max temp: 10sec.
- $\triangle$  Solder paste: Sn/3.0Ag/0.5Cu
- $\triangle$  Allowed Reflow time: 2x max

[Note: The reflow profile in the above table is only for qualification and is not meant to specify board assembly profiles. Actual board assembly profiles must be based on the customer's specific board design, solder paste and process, and should not exceed the parameters as the Reflow profile shows.]



# Sunlord



### 8. Supplier Information

- a) Supplier:
- Shenzhen Sunlord Electronics Co., Ltd.b) Manufacture:

Shenzhen Sunlord Electronics Co., Ltd.

c) Manufacturing Address:

Sunlord Industrial Park, Dafuyuan Industrial Zone, Guanlan, Shenzhen, China 518110